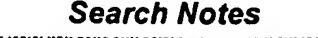


<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/601,475	KIM ET AL.
	Examiner Elizabeth Ivey	Art Unit 1775

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
see above		3/4	JL